



DMN3110S

**N-CHANNEL ENHANCEMENT MODE MOSFET**

**Product Summary**

$V_{(BR)DSS}$	$R_{DS(ON) \text{ max}}$	$I_D \text{ max}$ $T_A = 25^\circ\text{C}$
30V	73mΩ @ $V_{GS} = 10V$	3.3A
	110mΩ @ $V_{GS} = 4.5V$	2.7A

**Features and Benefits**

- Low On-Resistance
- Low Input Capacitance
- Fast Switching Speed
- **Lead Free By Design/RoHS Compliant (Note 1)**
- **"Green" Device (Note 2)**
- **Qualified to AEC-Q101 standards for High Reliability**

**Description and Applications**

This MOSFET has been designed to minimize the on-state resistance ( $R_{DS(on)}$ ) and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

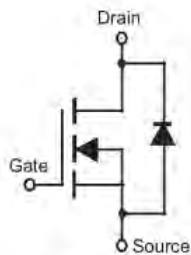
- General Purpose Interfacing Switch
- Power Management Functions
- Boost Application
- Analog Switch

**Mechanical Data**

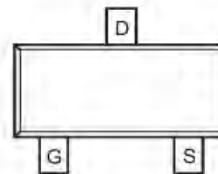
- Case: SOT-23
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections Indicator: See diagram
- Terminals: Finish — NiPdAu over Copper leadframe. Solderable per MIL-STD-202, Method 208
- Weight: 0.027 grams (approximate)



TOP VIEW



Internal Schematic



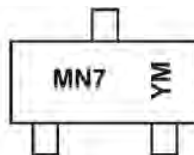
TOP VIEW

**Ordering Information** (Note 3)

Part Number	Case	Packaging
DMN3110S-7	SOT-23	3000/Tape & Reel

Notes: 1. No purposefully added lead.

**Marking Information**



MN7 = Product Type Marking Code  
 YM = Date Code Marking  
 Y = Year (ex: W = 2009)  
 M = Month (ex: 9 = September)

Date Code Key

Year	2009	2010	2011	2012	2013	2014	2015
Code	W	X	Y	Z	A	B	C

Month	Jan	Feb	Mar	Apr	May	Jun	Jul	Aug	Sep	Oct	Nov	Dec
Code	1	2	3	4	5	6	7	8	9	O	N	D

**Maximum Ratings** @T<sub>A</sub> = 25°C unless otherwise specified

Characteristic			Symbol	Value	Units
Drain-Source Voltage			V <sub>DSS</sub>	30	V
Gate-Source Voltage			V <sub>GSS</sub>	±20	V
Continuous Drain Current (Note 4) V <sub>GS</sub> = 10V	Steady State	T <sub>A</sub> = 25°C	I <sub>D</sub>	2.5	A
		T <sub>A</sub> = 70°C		2.0	
Continuous Drain Current (Note 5) V <sub>GS</sub> = 10V	Steady State	T <sub>A</sub> = 25°C	I <sub>D</sub>	3.3	A
		T <sub>A</sub> = 70°C		2.7	
Continuous Drain Current (Note 5) V <sub>GS</sub> = 10V	t ≤ 10sec	T <sub>A</sub> = 25°C	I <sub>D</sub>	3.8	A
		T <sub>A</sub> = 70°C		3.1	
Continuous Drain Current (Note 5) V <sub>GS</sub> = 4.5V	Steady State	T <sub>A</sub> = 25°C	I <sub>D</sub>	2.7	A
		T <sub>A</sub> = 70°C		2.1	
Pulsed Drain Current (Note 6)			I <sub>DM</sub>	25	A

**Thermal Characteristics** @T<sub>A</sub> = 25°C unless otherwise specified

Characteristic	Symbol	Value	Units
Total Power Dissipation (Note 4)	P <sub>D</sub>	0.74	W
Thermal Resistance, Junction to Ambient (Note 4)	R <sub>θJA</sub>	173.4	°C/W
Total Power Dissipation (Note 5)	P <sub>D</sub>	1.3	W
Thermal Resistance, Junction to Ambient (Note 5)	R <sub>θJA</sub>	99.1	°C/W
Total Power Dissipation (Note 5) t ≤ 10sec	P <sub>D</sub>	1.8	W
Thermal Resistance, Junction to Ambient (Note 5) t ≤ 10sec	R <sub>θJA</sub>	72	°C/W
Operating and Storage Temperature Range	T <sub>J</sub> , T <sub>STG</sub>	-55 to +150	°C

**Electrical Characteristics** @T<sub>A</sub> = 25°C unless otherwise specified

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
<b>OFF CHARACTERISTICS (Note 7)</b>						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	30	-	-	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA
Zero Gate Voltage Drain Current @T <sub>c</sub> = 25°C	I <sub>DSS</sub>	-	-	1.0	μA	V <sub>DS</sub> = 30V, V <sub>GS</sub> = 0V
Gate-Source Leakage	I <sub>GSS</sub>	-	-	±100	nA	V <sub>GS</sub> = ±20V, V <sub>DS</sub> = 0V
<b>ON CHARACTERISTICS (Note 7)</b>						
Gate Threshold Voltage	V <sub>GS(th)</sub>	1.0	-	3.0	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA
Static Drain-Source On-Resistance	R <sub>DS(on)</sub>	-	54	73	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 3.1A
		-	88	110		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 2A
		-	-	-		-
Forward Transfer Admittance	Y <sub>fs</sub>	-	4.8	-	mS	V <sub>DS</sub> = 10V, I <sub>D</sub> = 3.1A
Diode Forward Voltage (Note 6)	V <sub>SD</sub>	-	0.75	1.0	V	V <sub>GS</sub> = 0V, I <sub>S</sub> = 1A
<b>DYNAMIC CHARACTERISTICS (Note 8)</b>						
Input Capacitance	C <sub>iss</sub>	-	305.8	-	pF	V <sub>DS</sub> = 15V, V <sub>GS</sub> = 0V, f = 1.0MHz
Output Capacitance	C <sub>oss</sub>	-	39.9	-	pF	
Reverse Transfer Capacitance	C <sub>rss</sub>	-	39.5	-	pF	
Gate Resistance	R <sub>g</sub>	-	1.4	-	Ω	V <sub>DS</sub> = 0V, V <sub>GS</sub> = 0V, f = 1.0MHz
Total Gate Charge (V <sub>GS</sub> = 4.5V)	Q <sub>g</sub>	-	4.1	-	nC	V <sub>GS</sub> = 10V, V <sub>DS</sub> = 10V, I <sub>D</sub> = 3A
Total Gate Charge (V <sub>GS</sub> = 10V)	Q <sub>g</sub>	-	8.6	-	nC	
Gate-Source Charge	Q <sub>gs</sub>	-	1.2	-	nC	
Gate-Drain Charge	Q <sub>gd</sub>	-	1.5	-	nC	
Turn-On Delay Time	t <sub>D(on)</sub>	-	2.6	-	ns	V <sub>DD</sub> = 15V, V <sub>GS</sub> = 10V, R <sub>L</sub> = 47Ω, R <sub>G</sub> = 3Ω,
Turn-On Rise Time	t <sub>r</sub>	-	4.6	-	ns	
Turn-Off Delay Time	t <sub>D(off)</sub>	-	13.1	-	ns	
Turn-Off Fall Time	t <sub>f</sub>	-	2.5	-	ns	

- Notes:
2. Device mounted on FR-4 PCB, with minimum recommended pad layout.
  3. Device mounted on FR-4 substrate PC board, 2oz copper, on 1inch square copper plate
  4. Device mounted on minimum recommended pad layout test board, 10μs pulse duty cycle = 1%
  5. Short duration pulse test used to minimize self-heating effect.
  6. Guaranteed by design. Not subject to product testing.